

# EPC2901C\_55 – Enhancement Mode Power Transistor

$V_{DS}$ , 100 V

$R_{DS(on)}$ , 7 mΩ max

$I_D$ , 36 A

95% Pb/5% Sn Solder



Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

Maximum Ratings			
PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	100	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	120	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ , $R_{\theta JA} = 7.3$ )	36	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300 \mu\text{s}$ )	150	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-55 to 150	

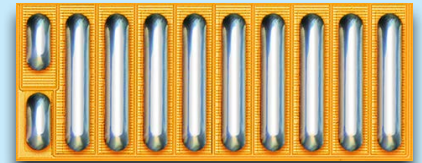
Thermal Characteristics			
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	2	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	54	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V}$ , $I_D = 300 \mu\text{A}$	100			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0 \text{ V}$ , $V_{DS} = 80 \text{ V}$		2	250	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}$ , $V_{DS} = 80 \text{ V}$ , $T_J = -55^\circ\text{C}$		0.9	50	
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5 \text{ V}$		0.019	2	mA
		$V_{GS} = 5 \text{ V}$ , $T_J = -55^\circ\text{C}$		0.01	1.5	
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 \text{ V}$		1.4	250	$\mu\text{A}$
	$V_{GS} = -4 \text{ V}$ , $T_J = -55^\circ\text{C}$		0.14	50		
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 5 \text{ mA}$	0.8	1.6	2.5	V
		$V_{DS} = V_{GS}$ , $I_D = 5 \text{ mA}$ , $T_J = -55^\circ\text{C}$		1.7	2.7	
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}$ , $I_D = 25 \text{ A}$		4.8	7	mΩ
		$V_{GS} = 5 \text{ V}$ , $I_D = 25 \text{ A}$ , $T_J = -55^\circ\text{C}$		3.1	6.5	
$V_{SD}$	Source-to-Drain Forward Voltage <sup>#</sup>	$V_{GS} = 0 \text{ V}$ , $I_S = 0.5 \text{ A}$		1.8		V

All measurements were done with substrate connected to source

<sup>#</sup> Defined by design. Not subject to production test



EPC2901C\_55 eGaN® FETs are supplied only in passivated die form with solder bars

### Applications

- High-Frequency DC-DC Conversion
- Industrial Automation
- Synchronous Rectification
- Low Inductance Motor Drives

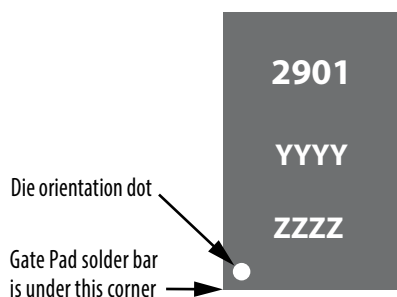
### Benefits

- Ultra High Efficiency
- Ultra Low Switching and Conduction Losses
- Zero  $Q_{RR}$
- Ultra Small Footprint

Dynamic Characteristics #( $T_J = 25^\circ\text{C}$ unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$C_{ISS}$	Input Capacitance	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		756	1020	pF
$C_{RSS}$	Reverse Transfer Capacitance			9.25	13	
$C_{OSS}$	Output Capacitance			493	650	
$C_{OSS(ER)}$	Effective Output Capacitance, Energy Related			567		
$C_{OSS(TR)}$	Effective Output Capacitance, Time Related			711		
$R_G$	Gate Resistance			0.3		$\Omega$
$Q_G$	Total Gate Charge	$V_{DS} = 50\text{ V}, V_{GS} = 5\text{ V}, I_D = 25\text{ A}$		6.9	10	nC
$Q_{GS}$	Gate to Source Charge	$V_{DS} = 50\text{ V}, I_D = 25\text{ A}$		1.9		
$Q_{GD}$	Gate to Drain Charge			1.35	2	
$Q_{G(TH)}$	Gate Charge at Threshold			1.2		
$Q_{OSS}$	Output Charge	$V_{DS} = 50\text{ V}, V_{GS} = 0\text{ V}$		36	45	
$Q_{RR}$	Source-Drain Recovery Charge			0		

All measurements were done with substrate connected to source  
 # Defined by design. Not subject to production test

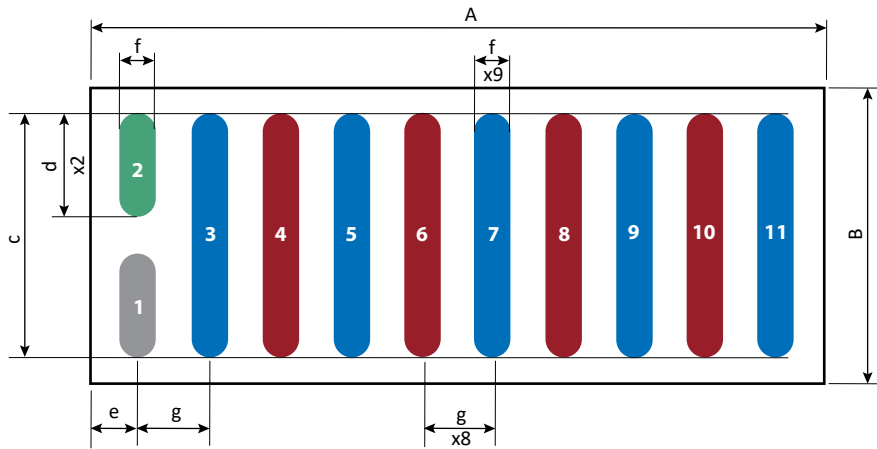
**DIE MARKINGS**



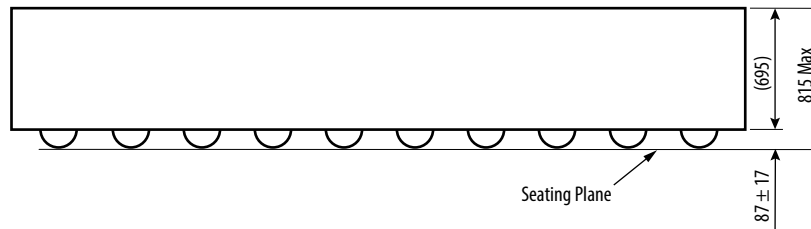
Part Number	Laser Markings		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2901C_55	2901	YYYY	ZZZZ

**DIE OUTLINE**

Solder Bar View



Side View

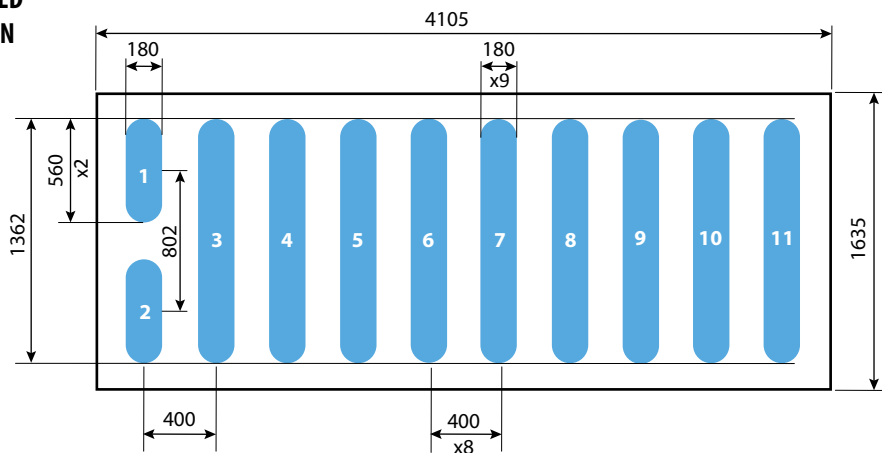


DIM	MICROMETERS		
	MIN	Nominal	MAX
A	4075	4105	4135
B	1605	1635	1665
c	1362	1382	1402
d	560	580	600
e	235	250	265
f	180	200	220
g		400	

Pad no. 1 is Gate;  
 Pads no. 3, 5, 7, 9, 11 are Drain;  
 Pads no. 4, 6, 8, 10 are Source;  
 Pad no. 2 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED LAND PATTERN**  
 (units in μm)

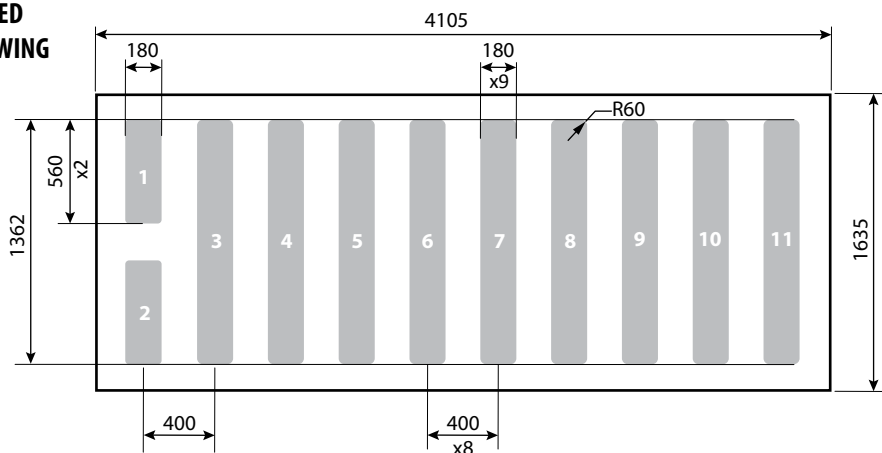


The land pattern is solder mask defined.

Pad no. 1 is Gate;  
 Pads no. 3, 5, 7, 9, 11 are Drain;  
 Pads no. 4, 6, 8, 10 are Source;  
 Pad no. 2 is Substrate.\*

\*Substrate pin should be connected to Source

**RECOMMENDED STENCIL DRAWING**  
 (units in μm)



Recommended stencil should be 4 mil (100 μm) thick, must be laser cut, opening per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at <https://www.epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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